



Effect of the thin Ga₂O₃ layer in n⁺-ZnO/n-Ga₂O₃/p-Cu₂O heterojunction solar cells

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ARTICLE INFO

Available online 3 July 2013

Keywords:

Cu₂O
Ga₂O₃
AZO
Solar cells
Thin film
Heterojunction

ABSTRACT

The influence of inserting a Ga₂O₃ thin film as an n-type semiconductor layer on the obtainable photovoltaic properties in Cu₂O-based heterojunction solar cells was investigated with a transparent conductive Al-doped ZnO (AZO) thin film/n-Ga₂O₃ thin film/p-Cu₂O sheet structure. It was found that this Ga₂O₃ thin film can greatly improve the performance of Cu₂O-based heterojunction solar cells fabricated using polycrystalline Cu₂O sheets that had been prepared by a thermal oxidation of copper sheets. The obtained photovoltaic properties in the AZO/Ga₂O₃/Cu₂O heterojunction solar cells were strongly dependent on the deposition conditions of the Ga₂O₃ films. The external quantum efficiency obtained in AZO/Ga₂O₃/Cu₂O heterojunction solar cells was found to be greater at wavelengths below approximately 500 nm than that obtained in AZO/Cu₂O heterojunction solar cells (i.e., prepared without a Ga₂O₃ layer) at equivalent wavelengths. This improvement of photovoltaic properties is mainly attributed to a decrease in the level of defects at the interface between the Ga₂O₃ thin film and the Cu₂O sheet. Conversion efficiencies over 5% were obtained in AZO/Ga₂O₃/Cu₂O heterojunction solar cells fabricated using an n-Ga₂O₃ thin-film layer prepared with a thickness of 40–80 nm at an O₂ gas pressure of approximately 1.7 Pa by a pulsed laser deposition.

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1. Introduction

Recently, we reported that n-type semiconductor/p-type Cu₂O heterojunction solar cells with a conversion efficiency of 3.83% could be fabricated by forming an Al-doped ZnO (AZO)/non-doped ZnO/Cu₂O structure on the front surface of polycrystalline Cu₂O sheets that had been prepared by a thermal oxidation of copper sheets [1]. This drastic improvement of conversion efficiency was made possible by the formation of an n-type ZnO thin-film layer (prepared with an appropriate thickness) using a low damage deposition technique on high quality polycrystalline Cu₂O sheets [2–4]. It is known that the obtainable open-circuit voltage is strongly dependent on the kind of n-type semiconductor layer used for forming the p–n heterojunction, such as the Cu₂O-based heterojunction [1–10]. In this regard, we have recently reported that the obtained conversion efficiency and the open-circuit voltage in n⁺-AZO/n-Zn_{1-x}Mg_xO/p-Cu₂O heterojunction solar cells (non-doped Zn_{1-x}Mg_xO thin films used as an n-type semiconductor layer) increased as the Mg content (Mg/(Zn + Mg) atomic ratio: x) was increased in the range from 0 to 0.09 [11]. In addition, it has been reported that the obtainable photovoltaic properties in n-semiconductor/p-Cu₂O heterojunction solar cells also are affected by the surface condition of the p-Cu₂O layer, that is, the interface at the heterojunction, rather than the diffusion potential resulting from the

difference of work functions between the p-Cu₂O and n-semiconductor layers [12–15]. We have reported more recently that a non-doped gallium oxide (Ga₂O₃) thin film is suitable as an n-semiconductor layer in n-semiconductor/p-Cu₂O heterojunction solar cells [16]. A high efficiency over 5% was obtained in an n⁺-AZO/n-Ga₂O₃/p-Cu₂O heterojunction solar cell fabricated with a non-doped Ga₂O₃ thin film as the n-semiconductor layer.

For this paper, the influence of inserting a non-doped Ga₂O₃ thin-film layer on the obtainable photovoltaic properties in Cu₂O-based heterojunction solar cells was investigated with a transparent conductive AZO thin film/n-Ga₂O₃ thin film/p-Cu₂O sheet structure. To improve the photovoltaic properties, the preparation conditions of the inserted non-doped Ga₂O₃ thin-film layer were optimized for use in n⁺-AZO/n-Ga₂O₃/p-Cu₂O heterojunction solar cells that were fabricated by forming this Ga₂O₃ thin film on the front surface of thermally oxidized Cu₂O sheets using a pulsed laser deposition (PLD) method.

2. Experimental

The solar cells were fabricated by forming an n⁺-AZO/n-Ga₂O₃/p-Cu₂O structure on the front surface of Cu₂O sheets (thickness of approximately 0.2 mm) and an Au ohmic electrode on the back surface; the Cu₂O sheets function as the active layer as well as the substrate, as shown in Fig. 1. The Cu₂O sheets were prepared by oxidizing Cu sheets using a heat treatment process that consisted of three steps in a furnace with a controlled ambient atmosphere [3,15]. The first step was annealing in an Ar gas atmosphere: Cu sheets (30 mm × 30 mm)

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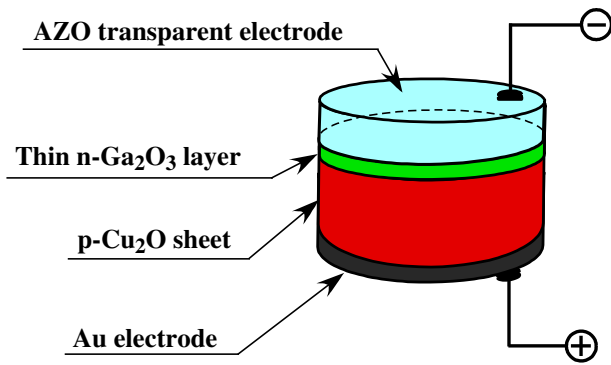


Fig. 1. Schematic structure of an AZO/n-Ga₂O₃/p-Cu₂O solar cell.

with a purity of 99.9% were heated up to 1025 °C at a rate of 17 °C/min and kept at this temperature for 1 h. The second step was oxidation in air: air was introduced into the furnace, and the temperature was kept at 1025 °C for 2 h. The third step resulted in the formation of superior Cu₂O: after the air was purged, an Ar gas atmosphere was introduced into the furnace, and then the sheets were annealed at 1025 °C for 2 h. Subsequently, the temperature was lowered to 500 °C at a rate of 8 °C/min, and finally, the Cu₂O sheets were brought out to the air environment at room temperature (RT). The resulting Cu₂O sheets were polycrystalline p-type semiconductors composed of grains whose size, in the range from approximately 1 to 100 nm², could be controlled by varying the heat treatment conditions described above. However, the obtained electrical properties, i.e., resistivity of 10²–10³ Ωcm, the hole concentration on the order of 10¹³ cm⁻³ and the Hall mobility above 100 cm²/Vs, were relatively independent of the observed grain size.

In the first step of device fabrication, the CuO surface layer of the oxidized Cu₂O sheets was removed by chemical wet etching. Subsequently, the AZO and Ga₂O₃ thin films were prepared with a PLD method using an ArF excimer laser (wavelength, 193 nm; repetition rate, 20 Hz; pulse width, 20 ns; and fluence, 350 mJ/cm²) under the following deposition conditions: target-substrate distance, 40 mm; deposition temperature, RT (not intentionally heated); target, sintered AZO or non-doped Ga₂O₃ pellets; and atmosphere and pressure, O₂ gas at 0 (vacuum below 10⁻⁴ Pa)–2.2 Pa. In order to evaluate the electrical and optical properties of the resulting AZO and Ga₂O₃ films, simultaneous depositions were also conducted on OA-10 glass (Nippon Electric Glass Co., Ltd.) substrates. The AZO thin films, used as the transparent electrode in all the heterojunction solar cells, were always prepared with a thickness of 150–300 nm at an O₂ gas pressure of 0.2 Pa. The AZO thin films exhibited a resistivity of approximately 8 × 10⁻⁴ Ωcm and a carrier concentration of approximately 6.5 × 10²⁰ cm⁻³. The work function of the AZO and Ga₂O₃ thin films and the Cu₂O sheets was evaluated from the wavelength dependence of the photoemission of electrons using ultraviolet photoelectron spectroscopy [17]. The photovoltaic properties of the solar cells (electrode area of 3.14 mm²) were evaluated by exposing only the AZO transparent electrode area to AM1.5G solar illumination (100 mW/cm²) at 25 °C.

3. Results and discussion

3.1. Effect of inserting the Ga₂O₃ thin-film layer

In addition to the photovoltaic properties of solar cells with an n-semiconductor thin film/p-Cu₂O sheet structure being considerably affected by the materials used as the n-type semiconductor layer, it is also known that these properties also are affected by the surface condition of the p-Cu₂O layer in Cu₂O-based heterojunction solar cells, that is, the interface at the heterojunction [12–15,18,19]. Consequently,

the obtainable photovoltaic properties such as the open-circuit voltage and the fill factor in Cu₂O-based heterojunction solar cells are considerably dependent on the method as well as the operating conditions that exist when depositing an n-semiconductor thin film. As a result of investigations, we recently have found that a non-doped Ga₂O₃ thin film prepared at RT by a PLD method is a very promising material for the n-semiconductor layer in n-semiconductor/p-Cu₂O heterojunction solar cells [16]. Typical current density–voltage (*J*–*V*) characteristics as a function of the Ga₂O₃ thin-film thickness are shown in Fig. 2 for n⁺-AZO/n-Ga₂O₃/p-Cu₂O heterojunction solar cells (fabricated with AZO and non-doped Ga₂O₃ thin films) measured under AM1.5G solar illumination. The Ga₂O₃ thin films were prepared at RT with O₂ gas introduced into the deposition chamber at a pressure of 1.7 Pa. As can be seen in Fig. 2, a drastic improvement of the *J*–*V* characteristic was obtained by the insertion of a Ga₂O₃ thin-film layer into an AZO/Cu₂O heterojunction solar cell. Both the open-circuit voltage (*V*_{OC}) and the short circuit current density (*J*_{SC}) were increased dramatically by inserting an n-Ga₂O₃ thin-film layer, even with a thickness of approximately 20 nm. In addition, the fill factor (*FF*) gradually improved as the Ga₂O₃ thin-film thickness was increased up to 50–75 nm. The obtained *V*_{OC}, *J*_{SC}, *FF* and conversion efficiency (*η*) as functions of the Ga₂O₃ thin-film thickness (*t*) are shown in Fig. 3 for the AZO/Ga₂O₃/Cu₂O heterojunction solar cells shown in Fig. 2. As can be seen in Fig. 3, *η* reached its peak at a thickness of 50–75 nm and then decreased as the thickness was increased further. The increase of *η* with increasing Ga₂O₃ thin-film thickness up to approximately 40 nm is related to increases of both *V*_{OC} and *J*_{SC}; however, the fluctuation of *η* at thicknesses above approximately 40 nm is attributed mainly to that of *FF*. The decrease in *FF* at thicknesses above approximately 75 nm may be attributed to the increase of series resistance resulting from the thickness increase because the Ga₂O₃ thin films used as the n-semiconductor layer exhibited very high resistivity, as described later. It should be noted that a *V*_{OC} of 0.80 V and a *η* of 5.38% were obtained in an AZO/Ga₂O₃/Cu₂O heterojunction solar cell fabricated with a Ga₂O₃ thin-film layer with a thickness of 75 nm.

As can be seen in Fig. 3(a), the obtained *J*_{SC} was markedly increased by inserting the n-Ga₂O₃ thin-film layer. In addition, the observed external quantum efficiency (EQE) in AZO/Ga₂O₃/Cu₂O heterojunction solar cells improved dramatically as the Ga₂O₃ thin-film layer thickness was increased from 0 to approximately 40 nm and then remained unchanged as the thickness was increased further. The EQE obtained in AZO/Ga₂O₃/Cu₂O heterojunction solar cells was always greater than that obtained in an AZO/Cu₂O heterojunction solar cell, ranging over the full gamut of observable EQE spectra. Typical normalized EQE spectra are shown in Fig. 4 for the AZO/Ga₂O₃/Cu₂O

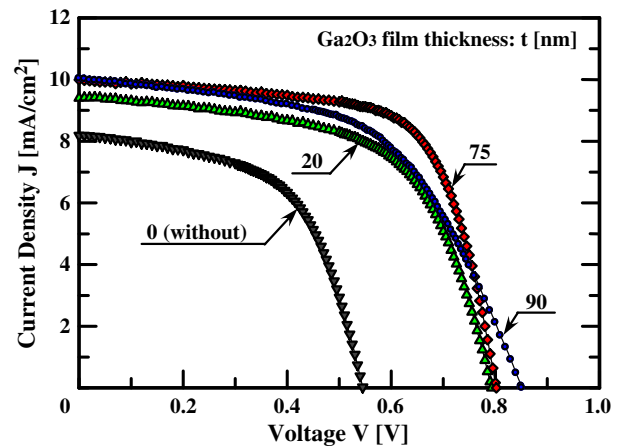


Fig. 2. *J*–*V* characteristics of AZO/Ga₂O₃/Cu₂O solar cells fabricated with various Ga₂O₃ film thicknesses (*t*): 0 (▽), 20 (Δ), 75 (◇) and 90 nm (○), measured under AM1.5G solar illumination.

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